



VAMAS



PRESTANDARDIZATION STUDY ON THE CHARACTERIZATION OF AIRBORNE NANOPARTICLES SIZE:

**Size characterization of
airborne SiO₂
nanoparticles with on-line
and off-line measurement
techniques: validation with
an interlaboratory
comparison**

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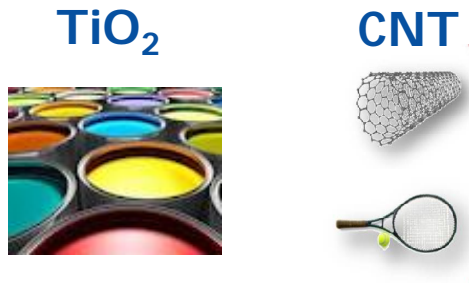
**MESURES
& RÉFÉRENCES**

Clés de la COMPÉTITIVITÉ
et d'un MONDE PLUS SÛR

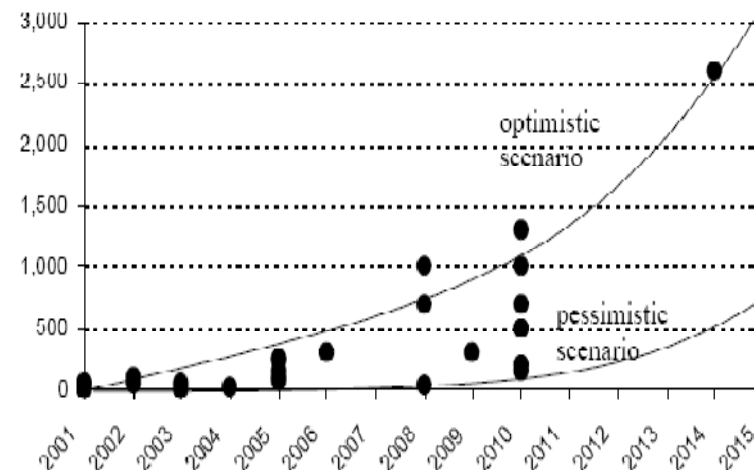
Laboratoire national de métrologie et d'essais

Context

- Production and use of manufactured nanoparticles, nano-objects, nanostructured powders and nanomaterials (ISO/TS 80004-1:2010) in \neq forms (TiO_2 , SiO_2 , NTC, Ag, Al_2O_3 ,...) by industry and research laboratories
- \neq Applications : environnement, energie, electronics, cosmetics, car industry construction, medicine, bio-technology, food...



World growing market for nanotechnology (billion US \$)



Nano-scale

$$1\text{nm} \leq d_p \leq 100\text{nm}$$

➔ Nano-object (nanofiber, nanoparticle, nanoplate)

ISO TS/27687: 2008



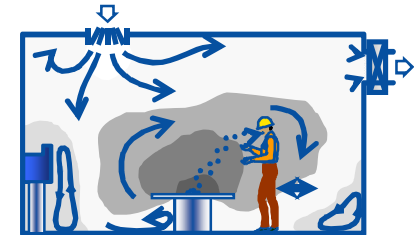
- **Potential Risks: General population, Environment and product**



Human protection



Atmospheric measurement



Process and workers

- **Need to have some airborne NP characterization metrological standard procedures**

➔ **To curb to reliable toxicology studies and ecotoxicology, quality control in industry, the monitoring, the reglementation which begin to arrive now in France** (*Décret 2012-232 du 17 février 2012 et arrêté du 6 août 2012 relatifs à la déclaration annuelle des substances à l'état nanoparticulaire*)

Project VAMAS



Objectives of VAMAS project

VAMAS : Versailles Project on Advanced Materials and Standards (1985)

- An international collaborative organization on prestandardization research projects and specifications for advanced materials

Objectives

- To develop size characterization methods for airborne nanoparticles that include the entire measurement chain (sampling, analysis, data process) which are traceable and accurate including metrological traceability, calibration, and evaluation of the measurement uncertainty.
- Validated the developed protocols by an interlaboratory comparison based on metrological approaches

Organisation

- The study performed within the framework of the **Technical Working Area (TWA) 34 - "Properties of Nanoparticle Populations"** of the VAMAS in the project n°3 **"Techniques for characterizing size distribution of airborne nanoparticles"**
- Mai 2009 - septembre 2012
- Participants :
 - LNE : leader du projet
 - 12 national Metrology Institutes : BAM (Germany), CENAM (Mexico), DFM (Denmark), NMI A (Australia), NMI SA (South Africa), INPL (Israel), KRISS (South Korea), LNE (France), NIST (USA), NPL (UK), NMI J-AIST (Japan) and NPLI (India)
 - 6 laboratories involved in nanoparticle metrology : LPMA (France), LISAF (France), ILAQH - SEF (Australia), UNC (Israel) and UNIGE (Italy)



Work plan: *project in 3 phases*

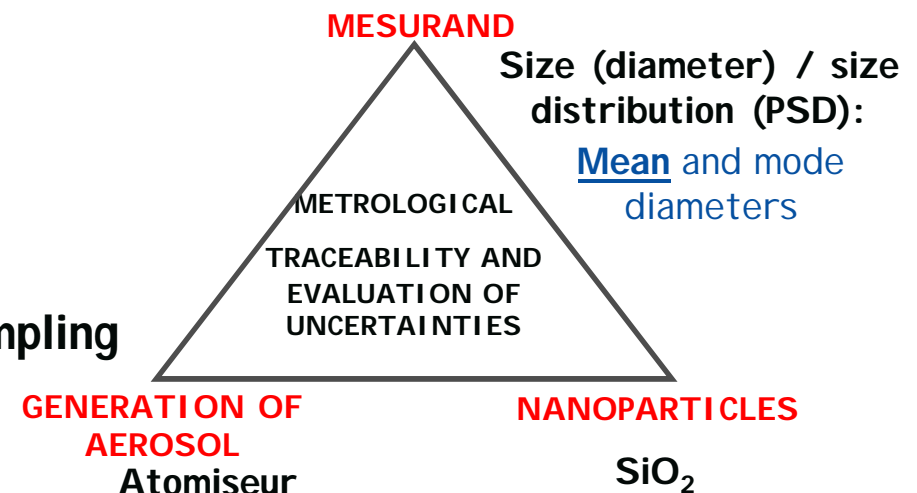
➤ **Phase 1:** Mai 2009 – June 2011

- Identification :

- > Mesurand,
- > Particules of interest,
- > Generation system of aerosol,
- > Techniques of measurements and of sampling

- Developpement of protocols

(generation, sampling and characterisation)



.....

➤ **Phase 2:** Mai 2011 – April 2012

- Evaluation of protocols developped

Interlaboratory comparison with on-line (SMPS) and off-line (AFM, MEB et TEM) measurement techniques

.....

➤ **Phase 3:** Mai 2011 – September 2012

- Analyse of results and validation of protocols



Project description

PSL (CRM) for SMPS calibration

SiO₂ Nanoparticles
in manufactured
colloidal suspension

Atomizer

2 types of Aerosol :

- One monodisperse population (35 nm)
- Two populations of primary particles without agglomeration (40 and 80 nm)

Round robin test 2

OP or DP suspension

4 types of sampling
under SMPS control

Generation system

Suspension characterization

TEM, AFM,
SEM and DLS

Techniques for airborne nanoparticles characterization

1

SMPS

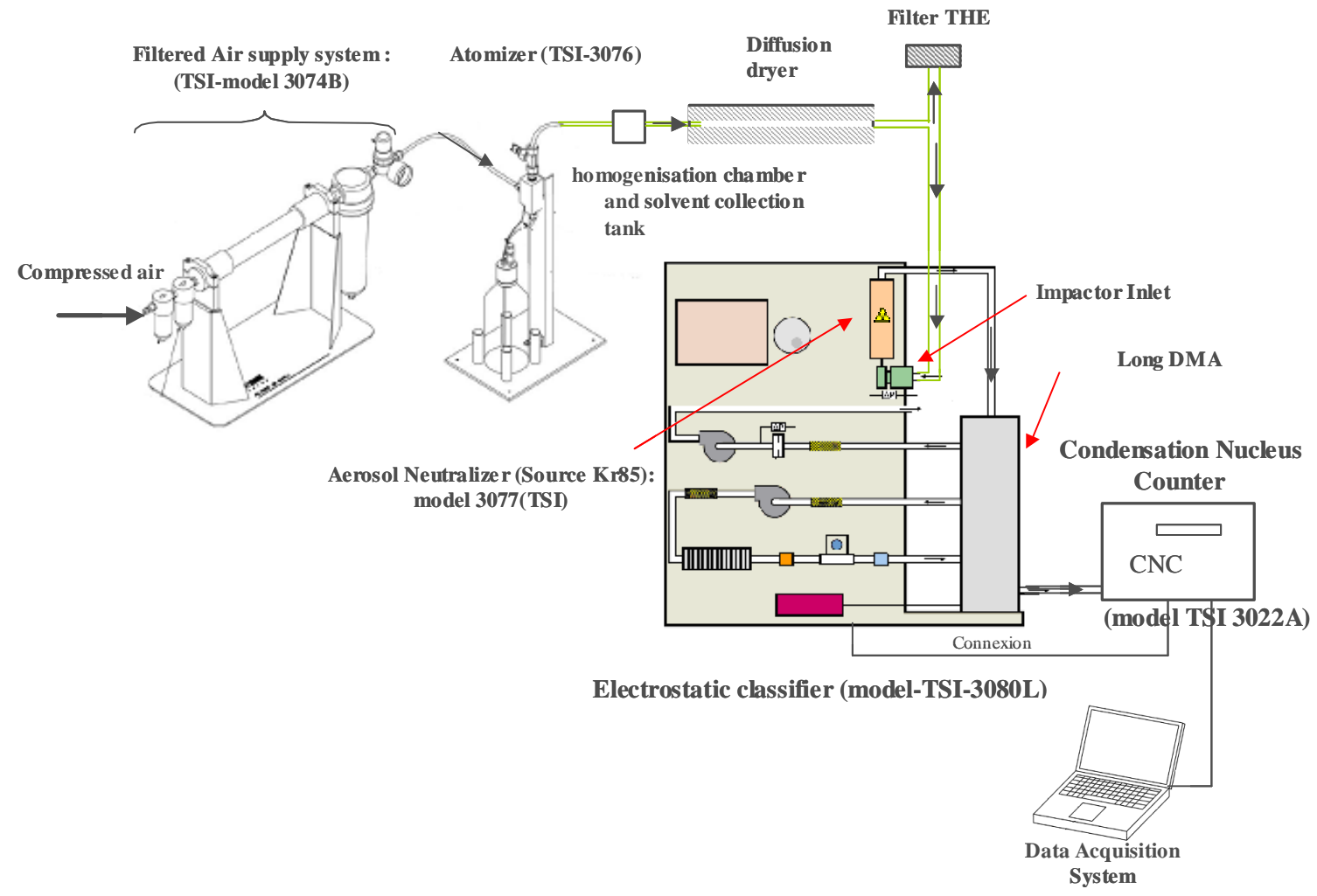
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Microscopy:
SEM, TEM, AFM

ISO 15900, Flow meter
calibration, voltage calibration

PSL, gold, height standard
(CRM) for calibration

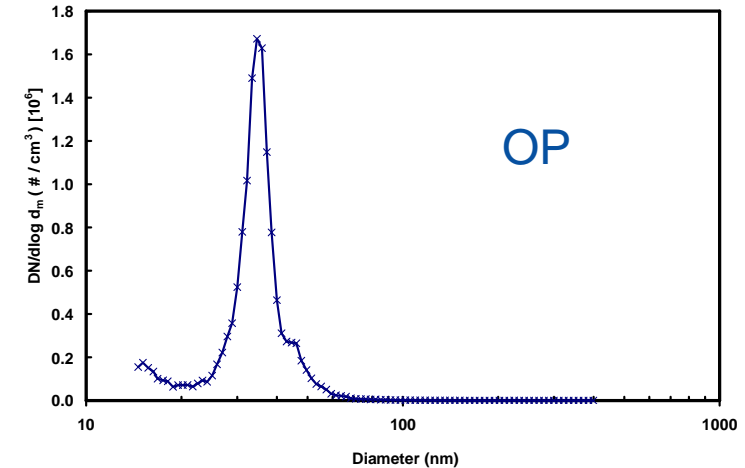
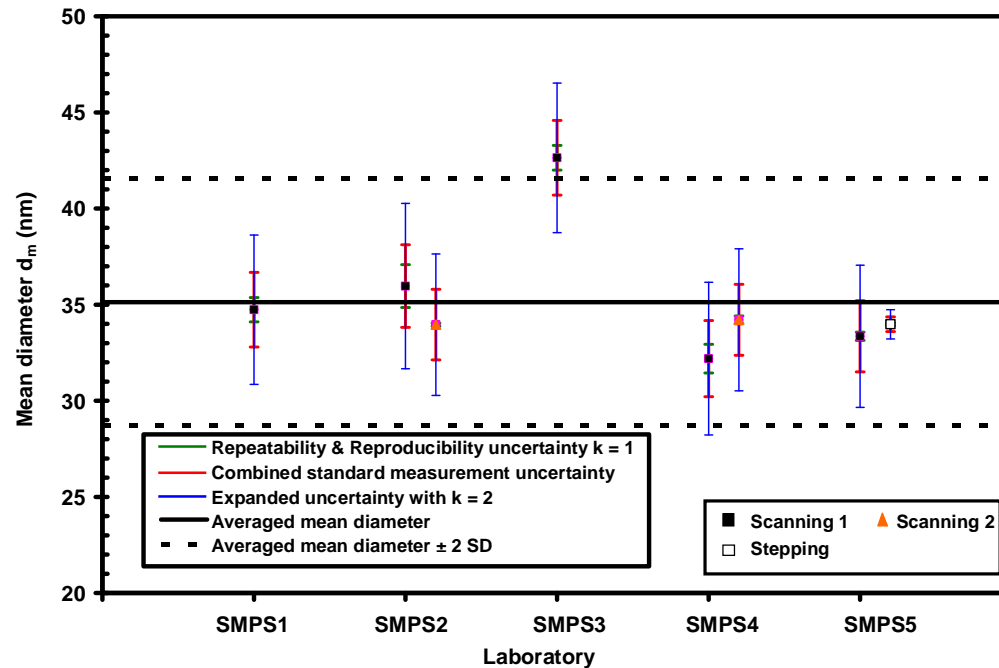
Using of Scanning Mobility Particle Sizer (SMPS)



- Preparation of colloïdales suspensions :
 - 2 manufactured colloïdales suspensions diluted with Milli-Q water in order to obtain 2 types of non-agglomerated nano-aerosols (1) a monodisperse population called "Aerosol One Population" (aerosol OP). (2) two nanoparticle populations (a bimodal PSD) called "Aerosol Double Population" (aerosol DP) of isolated (no-agglomerated) airborne particles
- Generation :
 - Cleaning procedure
 - Analyse of background
 - P = 2.4 bar with atomiser
- Measurement : SMPS
 - Scanning mode (Commercial software AIM)
 - Stepping mode (DMA moment method) with same DMA (3080, TSI)
- Traceability :
 - Calibration of DMA with PSL (CRMs) certified by TEM : 46 nm ± 2 nm, 81 nm ± 3 nm et 100.82 nm ± 0.66 nm (compliant to the standard ISO 15900 "Determination of particle size distribution - Differential electrical mobility analysis for aerosol particles")
- Results treatment :
 - Using different laws : gaussian (normal), asymmetric gaussian, and log-normal
 - Uncertainty evaluation : ISO 5725-2 (repeatability and reproducibility) et sources (≠ generators, DMA flow conditions, diffusion and charge corrections)



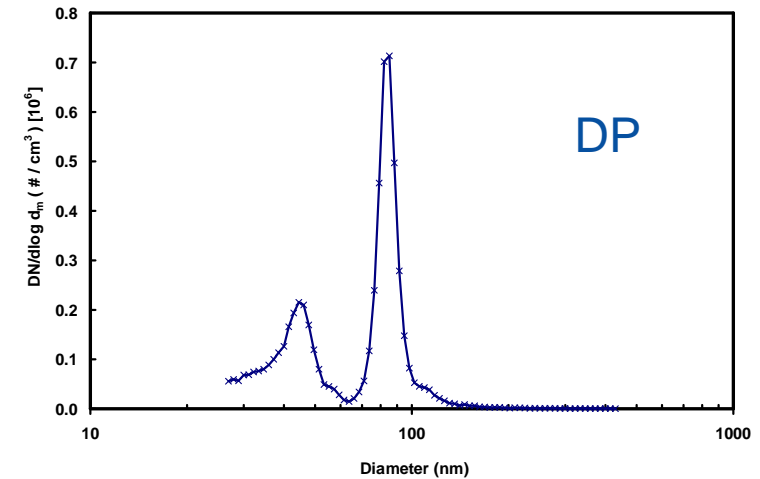
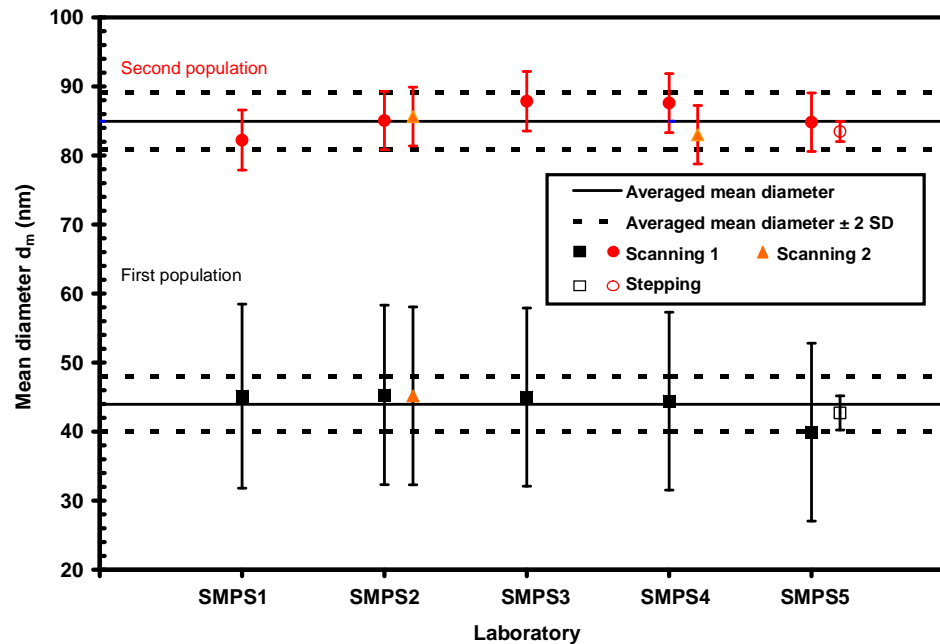
On-line measurement (SMPS): Results



- $32 \text{ nm} < d_p \text{ mean} < 36 \text{ nm}$, except SMPS3 (43 nm)
- $SD \text{ repro} \leq 1 \text{ nm} / U(k=2) \leq 4 \text{ nm}$
- **Influence of range used to determine the mean diameter** (\neq of 2 nm for atomiseur and \neq of 0,6 nm for electrospray)
- **Uncertainty stepping \leq scanning**



On-line measurement (SMPS): Results



- 1^{er} population : 39 nm < dp1 mean < 46 nm
2nd population : 82 nm < dp2 mean < 88 nm
- 1^{er} population : SD repro ≤ 2 nm / U(k=2) ≤ 13 nm
2^{ème} population : SD repro ≤ 0,5 nm / U(k=2) ≤ 4 nm
- **Influence of range used** to determine the mean diameter (≠ max of 5 nm)
- **Ratios in number concentration** between the 2 populations: peak et area

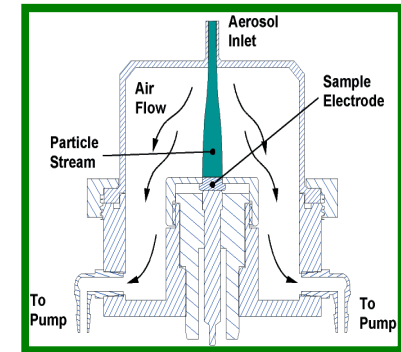


Off-line measurement: Sampling

2 types of sampling methods + 3 supports types

1 - Filtration (Diffusion-impaction-interception) → - Polycarbonate membrane filter (PMF)
 - Grilles TEM deposited on PMF

2 - Electrostatic precipitation (NAS) → MI CA and TEM Grids



➤ Sampling performed by 4 laboratories :

4 types of samples :

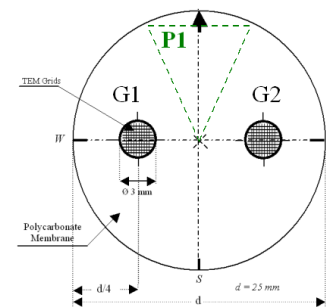
- Sample A (filtration + 2 TEM grids « G »)
- Sample B (NAS + Grids « N1, N2, N3 et N4 »)
- Sample C (filtration + PC alone « F1, F2 et F2 »)
- Sample D (NAS + MI CA « M1, M2 et M3 »)

➤ **Protocols of sampling**
(scientific literature + consensus)

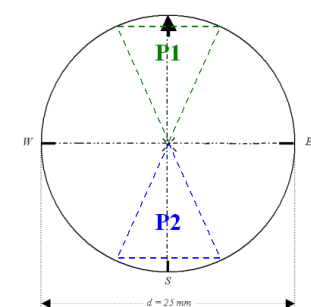
(Q, diameter of the filters and the pores, sampling time,...)

➤ **Protocols for storage conditions and sample transport**

Sample A :
PMF (F1, F2, F3) + 2 TEM grids (G1, G2)



Sample C :
PMF (F1, F2, F3) only



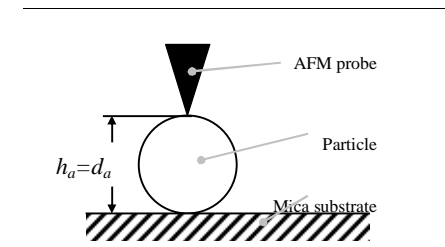
Part P₁ : for transfer on TEM grids (g1, g2)
 Part P₂ : used for SEM



Samples preparation :

Examples :

- SEM with high-voltage : Coating
- MET : Transfer of particles from PMF to TEM grids

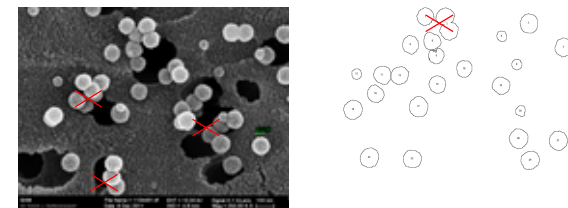


Protocole de mesures :

Mesurand / Conditions of measurement / Materials / Traceability (CRM) / Number of measured particles :

Example for AFM: maximum particle height (Apex) / 2 CRM for the metrologic comparability (*calibrated step height of 41.2 ± 0.7 nm and PSL with a mean calibrated diameter of 46 ± 2 nm certified by TEM*) / scan range = $2 \times 2 \mu\text{m}$ / image size: 512×512 pixels / Tapping or intermittent mode / Supersharp tips / Recommendation of a minimum of 400 measured particles per sample per sample in order to allow a reasonable statistical evaluation of the PSD ...

Results treatment : Images treatment



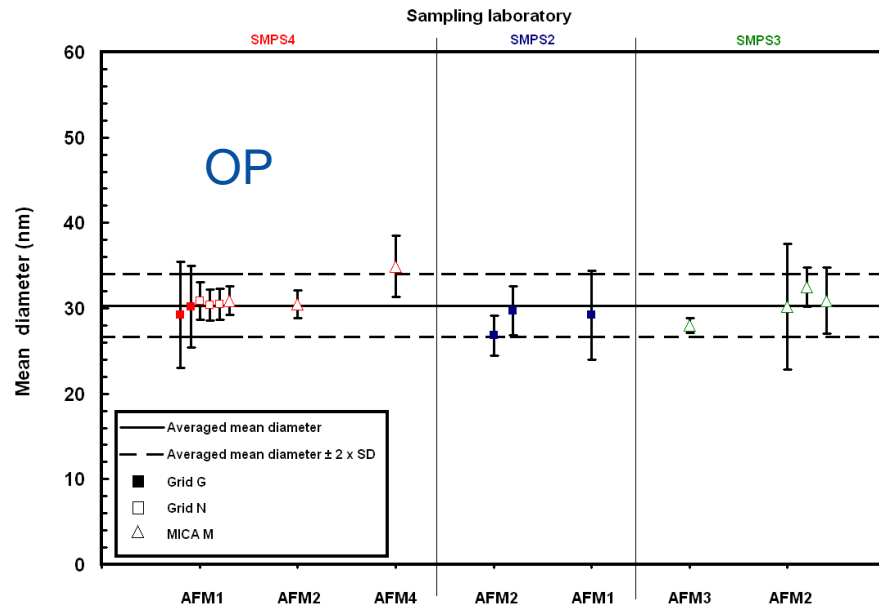
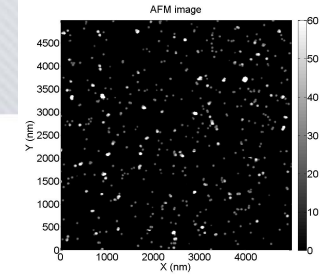
Measurement uncertainty evaluation :

Estimation by each participants in function of their measurement methods, data treatment and of their instrumentation : contribution of several sources

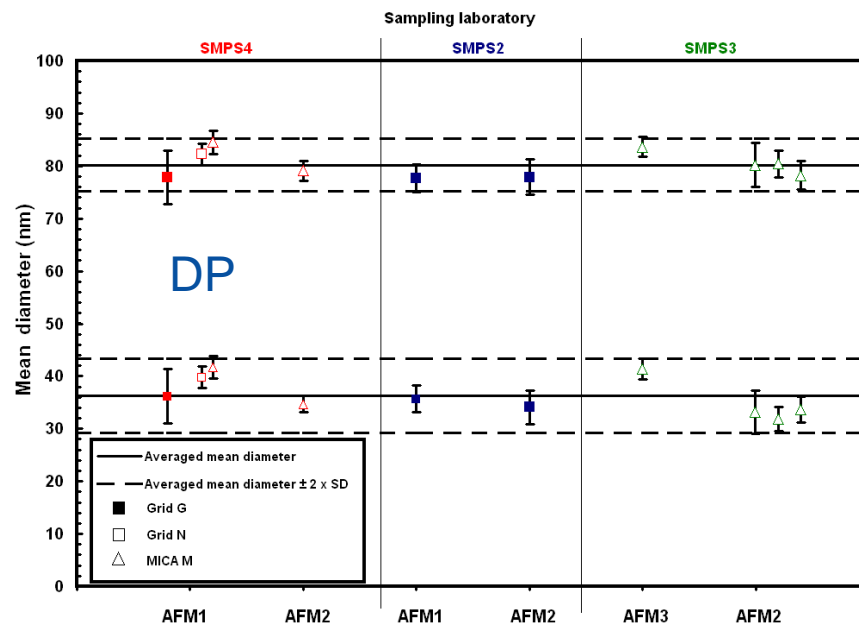
Example for SEM and TEM: correction or taken into account of the coating thickness, calibration of the magnification, threshold in the greyscale images.



Off-line measurement: AFM Results



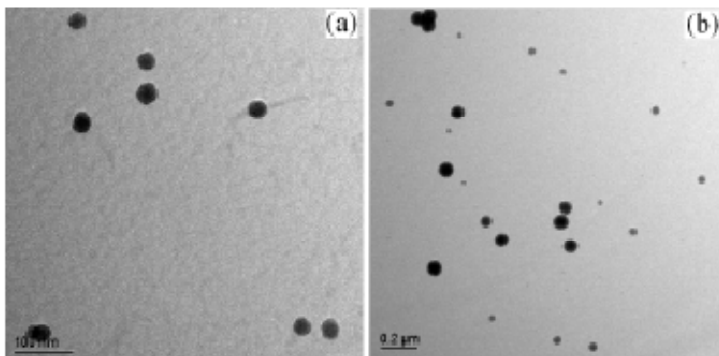
- 4 laboratories involved
- Good agreement between the results of different participants
- 27 nm < dp mean < 33 nm, except AFM4 (35 nm)
- $U(k=2) \leq 7$ nm / total mean average = 30.3 ± 3.7 nm
- No significant difference between the \neq samples types (Samples A, B et D)
- **The Lowest uncertainty obtained with MICA**



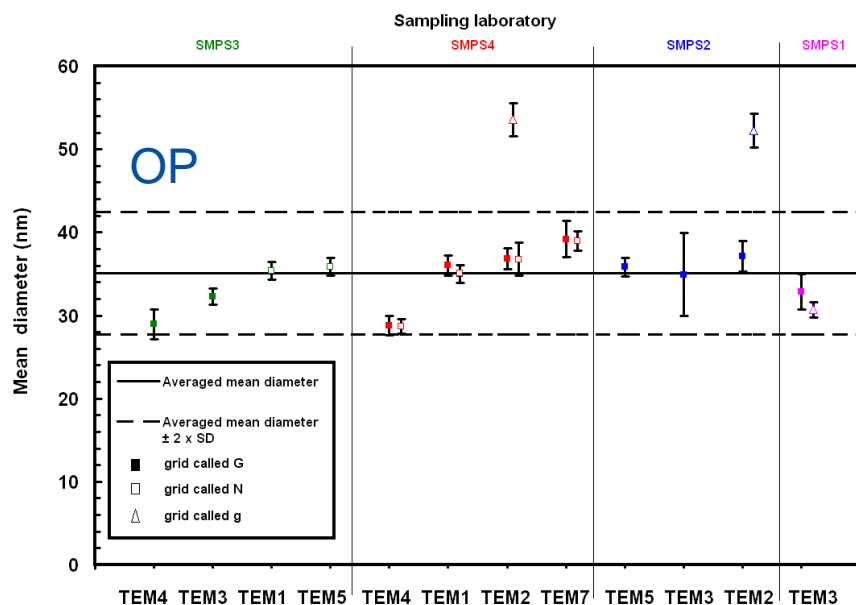
- Good agreement between the results of different participants
- 1^{er} population : 32 nm < dp1 mean < 42 nm
2nd population : 78 nm < dp2 mean < 85 nm
- $U(k=2) \leq 5$ nm for 1^{er} population and 2nd population
- Total mean averages = 36.2 ± 7.1 nm / 80.2 ± 5.0 nm
- **Ratios in number concentration between the 2 populations: peak et area**

Off-line measurement: TEM Results

7 laboratories involved



- $29 \text{ nm} < dp_{\text{mean}} < 39 \text{ nm}$, **except for the g grids (transfer)**
- $U(k=2) \leq 5 \text{ nm}$ / Total mean average = $35.1 \pm 7.4 \text{ nm}$
- **High difference** between the grids G and g (17 nm): **influence of transfer**

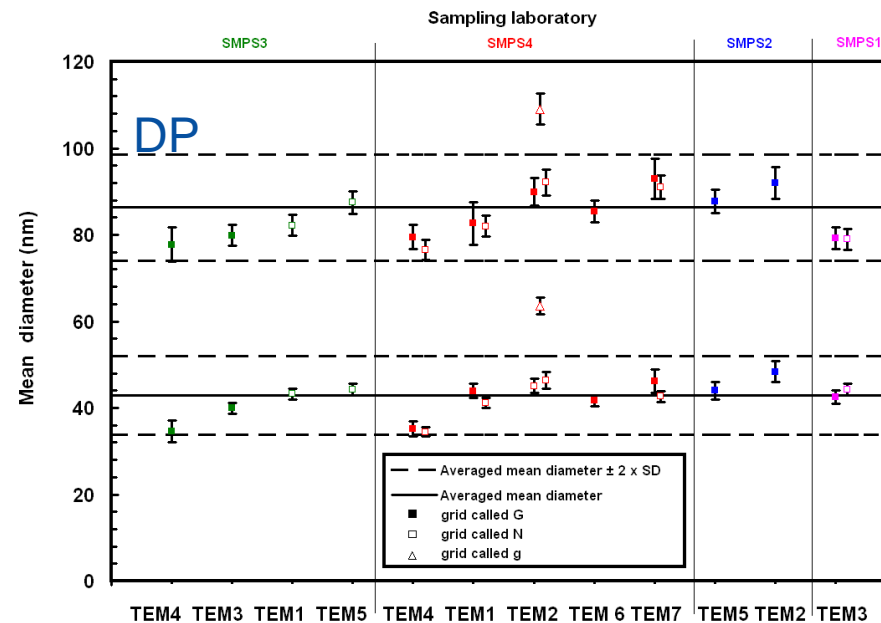


For TEM, avoid to use the transfer of particles from filter to TEM and choose to use the direct deposition on grids: **High impact on PSD**



Off-line measurement: TEM Results

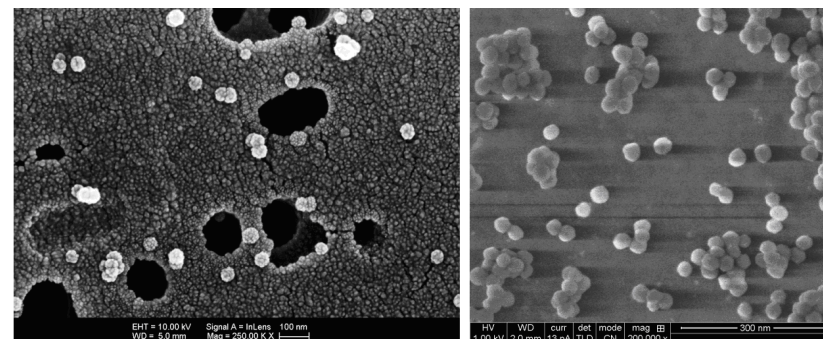
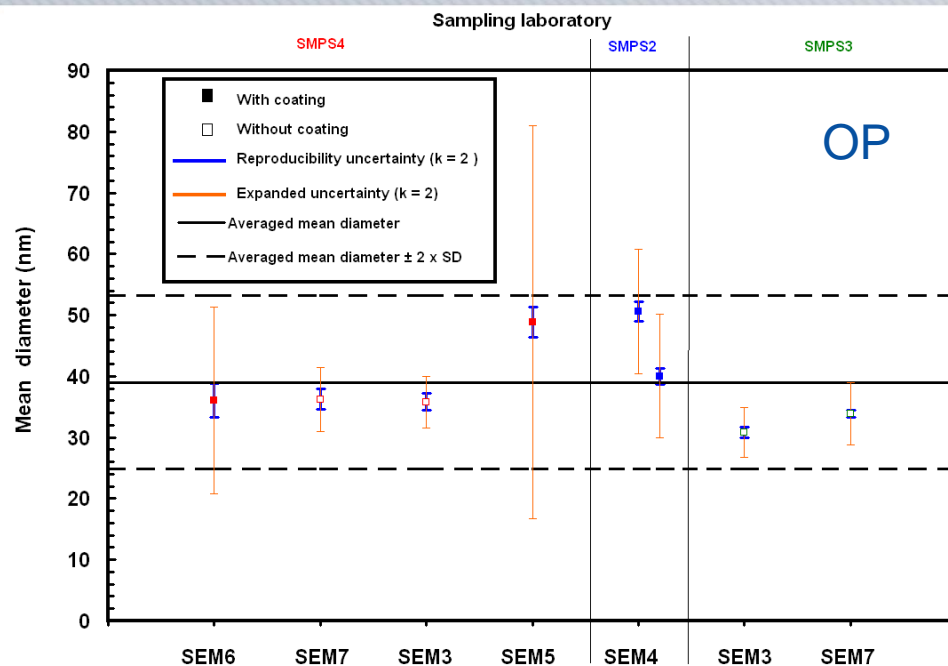
7 laboratories involved



- 1^{er} population : 35 nm < dp1 mean < 49 nm
- 2nd population : 77 nm < dp2 mean < 92 nm **except for the g grids (transfer)**
- $U \leq 5$ nm for 1^{er} population and 2nd population
- Total mean average = 42.9 ± 9.0 nm / 86.3 ± 12.3 nm
- **Ratios in number concentration between the 2 populations: peak et area**



Off-line measurement: SEM Results



7 laboratories involved

- 30 nm < dp mean < 51 nm
- **High dispersion of results : SD interlabo for SEM >> AFM and TEM**
- SD repro ≤ 3 nm
- $U(k=2) \leq 5$ nm **without coating**
 $U(k=2) \leq 32$ nm **with coating**
- Total mean average = 39.0 ± 14.2 nm

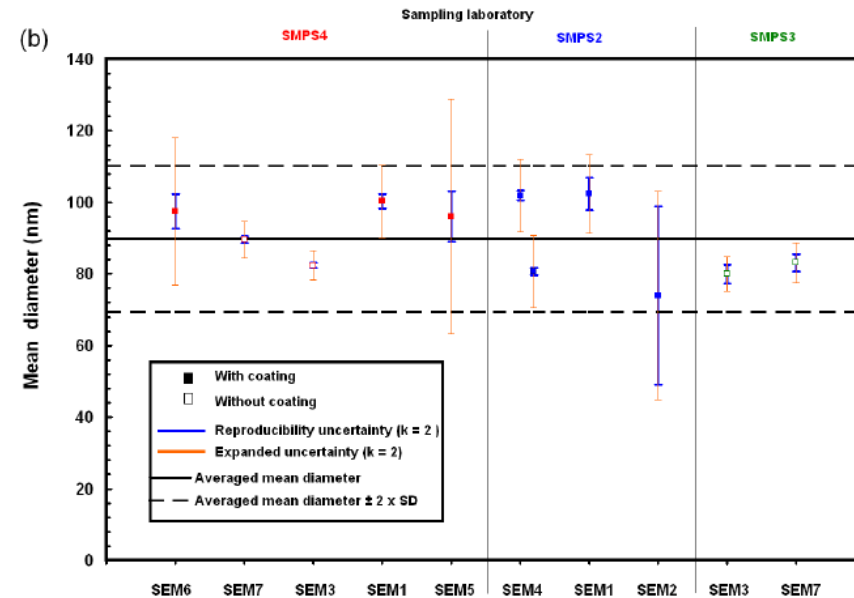
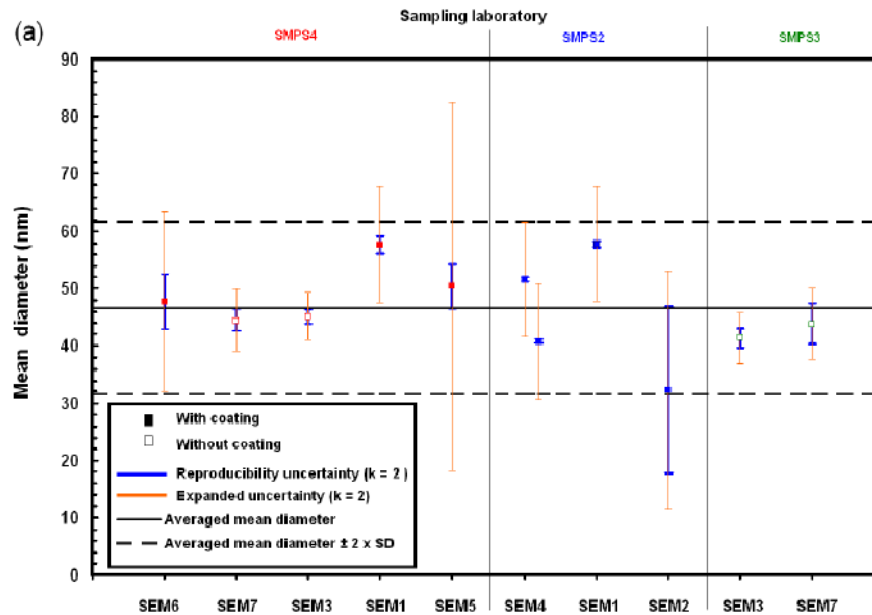
➤ **The Lowest uncertainties** were obtained for the low-voltage SEM (without coating)



Off-line measurement: SEM Results

DP

7 laboratories involved



- 1^{er} population : 32 nm < dp1 mean < 58 nm
- 2nd population : 74 nm < dp2 mean < 102 nm

- SD repro ≤ 7 nm for 1^{er} population and 2nd population except SEM2

- $U(k=2) \leq 5$ nm **without coating**
- $U(k=2) \leq 32$ nm **with coating**

- Total mean averages = 46.6 \pm 15.1 nm / 89.8 \pm 20.4 nm

- **Ratios in number concentration between the 2 populations: peak et area**

For SEM , don't use coating : high impact on PSD and strong increase of measurement uncertainty

Summary of results

OP

	Averaged mean diameter d_p (nm)	2* SD (nm)	Averaged mode diameter d_p (nm)	2* SD (nm)
SMPS	35.1	6.4	35.4	2.0
TEM	35.1	7.4	35.6	7.6
SEM	39.0	14.2	38.3	14.1
AFM	30.3	3.7	30.4	5.1

DP

	First population				Second population			
	Averaged mean diameter d_p (nm)	2* SD (nm)	Averaged mode diameter d_p (nm)	2* SD (nm)	Averaged mean diameter d_p (nm)	2* SD (nm)	Averaged mode diameter d_p (nm)	2* SD (nm)
SMPS	44.0	4.0	44.2	5.3	85.0	4.1	83.1	3.4
TEM	42.9	9.0	43.7	11.9	86.3	12.3	88.1	12.0
SEM	46.6	15.1	47.0	13.8	89.8	20.1	91.1	19.8
AFM	36.2	7.1	39.2	6.8	80.2	5.0	81.0	5.3

➔ Comparable results by techniques: validation of PSD characterization protocols

➔ Comparable results between techniques :



implementation of different techniques : ≠ **diameters types** (mobility, height, ...)

Spherical particles (equivalence of diameters)



- **Development and validation of generation protocols of 2 nano-aerosols types** : OP and DP isolated airborne nanoparticles (non-agglomerated)
- **Development of sampling protocols** for off-line measurements by **2 methods** (filtration and electrostatic precipitation) on appropriate supports (grids, filters and MI CA plates)
- **Development and validation of procedures for the size distribution characterization of SiO₂ airborne nanoparticles** by on-line (SMPS) and off-line (MEB, MET et AFM) techniques: mean and mode diameters
- **Interlaboratory comparison with metrological approaches** (metrological traceability, calibration, and evaluation of the measurement uncertainty)
- **Recommendations**



- To provide measurements protocols accurate, reliable and robust and to give recommendations (scientific community, industry, legislative and regulatory authorities, etc.).

- To answer some needs
 - ➡ To perform reliable toxicology studies,
 - ➡ Quality control in industry and monitoring

- To provide Internationally harmonized measurement procedures for spherical airborne nanoparticles characterization for organizations in charge of standardization (CEN, ISO) in order to disseminate consensual and applicable standards for the size characterization of airborne nanoparticles

- ➡ Transfer of this work in standardization committees (AFNOR, ISO):

Submission by AFNOR of a New Work Item Proposal for a project of International Standard (IS) « On-line/off-line techniques for characterizing size distribution of airborne nanoparticle population »



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RESEARCH PAPER

Size characterization of airborne SiO₂ nanoparticles with on-line and off-line measurement techniques: an interlaboratory comparison study

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Abstract Results of an interlaboratory comparison on size characterization of SiO₂ airborne nanoparticles using on-line and off-line measurement techniques are discussed. This study was performed in the framework of Technical Working Area (TWA) 34—“Properties of Nanoparticle Populations” of the Versailles Project on Advanced Materials and Standards (VAMAS) in the project no. 3 “Techniques for characterizing size distribution of airborne nanoparticles”. Two types of nano-aerosols, consisting of (1) one population of

nanoparticles with a mean diameter between 30.3 and 39.0 nm and (2) two populations of non-agglomerated nanoparticles with mean diameters between, respectively, 36.2–46.6 nm and 80.2–89.8 nm, were generated for characterization measurements. Scanning mobility particle size spectrometers (SMPS) were used for on-line measurements of size distributions of the produced nano-aerosols. Transmission electron microscopy, scanning electron microscopy, and atomic force microscopy were used as off-line measurement

Internationally harmonized measurement procedures for airborne SiO₂ nanoparticles characterization



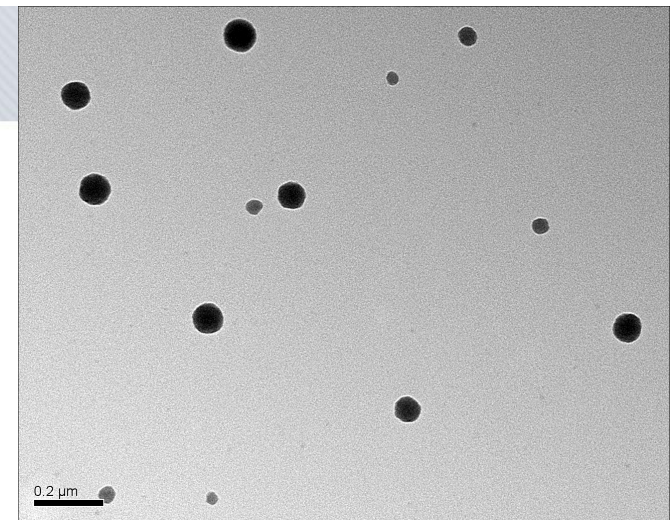
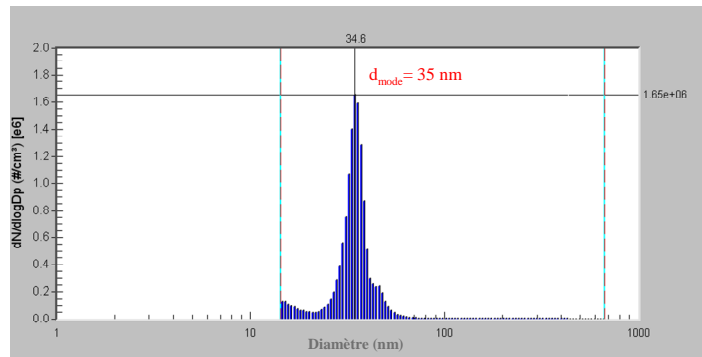
* NPLI, NPL and NIST were involved in this project but they didn't participate in the round robin test.



- By our knowledge, it would be interesting **to work on more complex particles** (CNT,...)
- **To work on the development of procedures** internationally harmonized with metrological approach to the **other relevant parameters** identified by the ISO TC 229 "Nanotechnology" and the OECD (Organisation for Economic Co-operation and Development)

Surface area, shape, surface charge, aggregation/agglomeration state, chemical composition (crystallinity, purity/impurity, global chemical composition), surface chemistry solubility/dispersibility





Thank you for your attention

